

**Notice of References Cited**

Application/Control No.

10/075,750

Applicant(s)/Patent Under  
Reexamination  
GAUTHIER ET AL.

Examiner

Cassandra Cox

Art Unit

2816

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,460,001	10-2002	Yamaguchi et al.	702/69
	B	US-6,441,602	08-2002	Eckhardt et al.	324/76.53
	C	US-6,333,905	12-2001	Kobayashi et al.	369/59.11
	D	US-5,828,255	10-1998	Kelkar et al.	327/157
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Measuring Jitter and Phase Error in Microprocessor Phase-Locked Loops, Keith A. Jenkins and James P. Eckhardt, IEEE Design & Test of Computers, Apr.-Jun. 2000, pp. 86-93.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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